

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No.10/632,273
Filing Date July 31, 2003
Inventor..... Warren M. Farnworth et al.
Assignee..... Micron Technology, Inc.
Group Art Unit.....2829
Examiner Russell M. Kobert
Attorney's Docket No.MI22-2379
Customer No.....021567
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether the submitted references are prior art.

This is a second submission of this Supplemental Information Disclosure Statement and Form PTO-1449 (originally filed April 16, 2007) since the first submission was inadvertently filed without a proper signature.

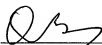
The fee for submission of this Supplemental Information Disclosure Statement was paid on April 16, 2007, therefore it is believed that no fees are due at this time. However, in the event that a fee is required for filing this Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date:

4-18-07



D. Brent Kenady
Reg. No. 40,045

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-2379SERIAL NO.
10/632,273LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Warren M. FarnworthFILING DATE
July 31, 2003GROUP
2829

U.S. PATENT DOCUMENTS

| Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
|------------------|----|-----------------|------|------|-------|----------|----------------------------|
| | AA | | | | | | |
| | AB | | | | | | |
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| | AL | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | Document Number | Date | Country | Class | Subclass | Translation | |
|--|----|-----------------|---------------|--------------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| | AM | 3-69131 | 8/1998 | Japan | | | X | |
| | AN | | | | | | | |
| | AO | | | | | | | |
| | AP | | | | | | | |
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.